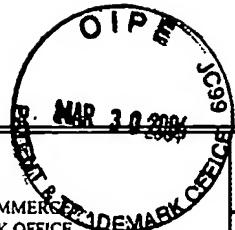




FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 03500.017883		APPLICATION NO. 10/769,765		
			APPLICANT HIROSHI AOTO ET AL.				
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			FILING DATE February 3, 2004		GROUP 286 Unassigned		
March 16, 2004							
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
MMT	3,946,398	03/1976	Kyser et al.	347	70		
	4,584,590	04/1986	Fischbeck et al.	347	69		
	5,265,315	11/1993	Hoisington et al.	29	25.35		
	6,653,211 B2	11/2003	Unno et al.	438	479		
	09/880,757 2002/0076875 A1	06/2002	Wasa et al.	029	025.30	pending	
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	6,927,084 2003/0196745 A1	08/2005 10/2003	Fukui et al.	438	021.000		
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
MMT	JP 53-12138	04/1978	Japan			*	
MMT	JP 6-350154	12/1994	Japan			Abstract	
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
MMT	*U.S. Patent No. 3,946,398 is a counterpart to JP 53-12138.						
EXAMINER	S. of Shuk		DATE CONSIDERED		11-16-05		

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicants.

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FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 03500.017883	APPLICATION NO. 10/769,765		
			APPLICANT HIROSHI AOTO ET AL.			
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			FILING DATE February 3, 2004	GROUP 2853		
October 13, 2005						
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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>MMK</i>	5,265,315	11/1993	Hoisington et al.			
<i>MMK</i>	4,584,590	04/1986	Fischbeck et al.			
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FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
<i>MMK</i>	0 656 429 A	06/1995	Europe			Yes
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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)						
<i>MMK</i>	OGAWA et al., "Controlling The Crystal Orientations of Lead Titanate Thin Films", Japanese Journal of Applied Physics, Tokyo, Japan, vol. 30, no. 9B, September 1, 1991, pps. 2145-2148					
<i>MMK</i>	LIN et al., "Epitaxial Growth of Pb(Zr <sub>0.2</sub> Ti <sub>0.8</sub> )O <sub>3</sub> On Si and its Nanoscale Piezoelectric Properties", Applied Physics Letters, American Institute of Physics, New York, USA, vol 78, no. 14, April 2, 2001, pps. 2034-2036					
EXAMINER	<i>S. H. Rich</i>		DATE CONSIDERED	<i>11-16-05</i>		

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